

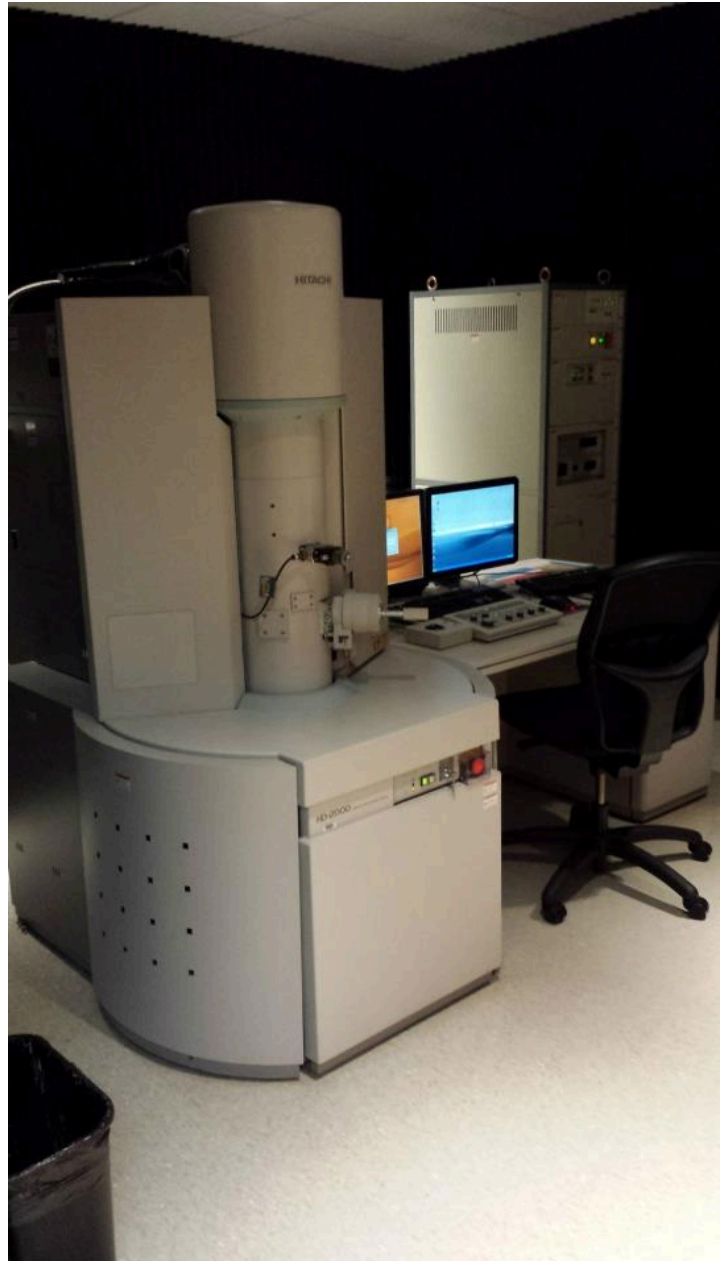
Scanning Transmission Electron Microscope – HD2000

Source – Field Emission

Resolution - 0.24 nm at 200 kV

Magnification – X 2,000,000

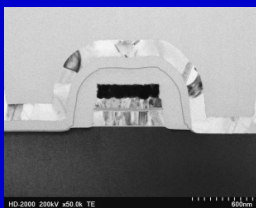
- Fast sample throughput
20 to 30 times faster than TEM
- Chemical analysis with EDS
- Ideally suited for industrial applications where faster sample throughput and TEM resolution is required.



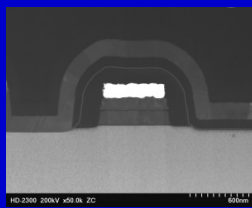
Energy Dispersive
Spectroscopy (EDS)

Spot/Linescan/Mapping
0.8nm/0.5nm/0.3nm

STEM images (TE/ZC)



Phase contrast image



Z contrast image

EDX Mapping of A Magnetic Head GMR

